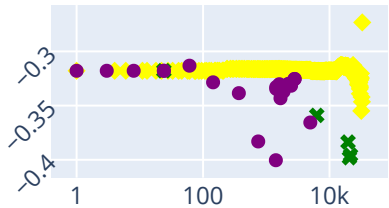
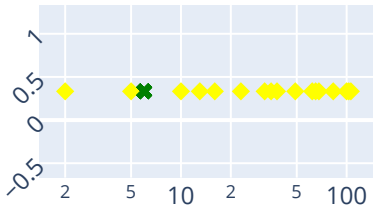


test loss

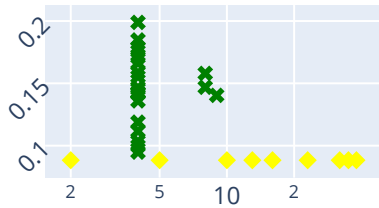
Circuit Recovery (IOI)



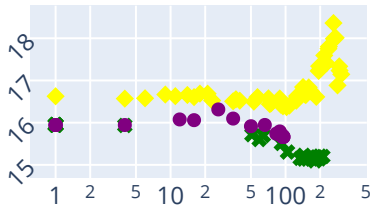
tracr-reverse



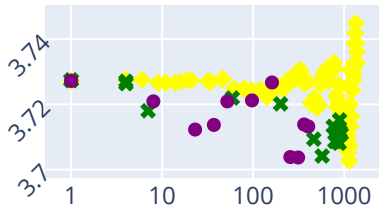
tracr-xproportion



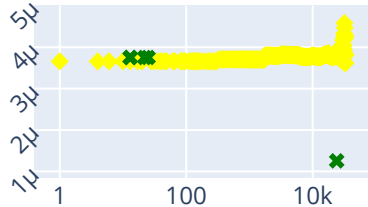
Induction



Docstring



Greater-Than



Number of edges